Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/519,672	MATSUHASHI ET AL.	
Examiner	Art Unit	

David E. Bochna

3679

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH N (INCLUDING SEARC		)
	. DATE	EXMR
Updated the previous search	6/3/2007	DB